

THAT WHICH IS CLAIMED IS:

1. A method of reading a capacitive sensor constituted by an array of capacitors ordered in rows and columns functionally connected through row lines, each electrically constituting a first plate of all the
5 capacitors of a row, and through column lines, each electrically constituting a second plate of all the capacitors of a column, orthogonal or quasi-orthogonal to each other, using a biasing and reading circuit (READOUT) comprising column and row selectors, a charge
10 amplifier outputting a voltage (V_0) function of the capacitance of a selected capacitor (C_{PIX}) of said array, comprising the steps of:

preliminarily resetting the output voltage (V_0) of said charge amplifier;
15 connecting to a reference voltage all the deselected row and column plates of said array and connecting an auxiliary capacitor (C_R) and said selected capacitor (C_{PIX}) to an inverting input (-) of the amplifier and as feedback capacitor of said amplifier,
20 respectively, or viceversa;

applying a step voltage (V_I) on the capacitor (C_R , C_{PIX}) that is connected to the inverting input (-) of the amplifier and reading at steady-state, said output voltage (V_0).

2. The method of claim 1, wherein the reading of the sensor includes a sequential scanning of the capacitors of the array, obtaining a frame of as many values of capacitance of the sensor.

3. The method of claim 2, wherein the scan is repeated with a certain frame frequency.

4. An integrated system for reading a capacitive sensor constituted by an array of capacitors

ordered in rows and columns functionally connected through row lines, each electrically constituting a first plate of all the capacitors of a row, and through column lines, each electrically constituting a second plate of all the capacitors of a column, orthogonal or quasi-orthogonal to each other, comprising:

an input interface circuit (ANAI/O) for coupling therethrough said capacitive sensor, the interface circuit grounding deselected row plates and column plates of said array and connecting a single capacitor (C_{PIX}) at the time selected by row and column selectors;

a biasing and reading circuit (READOUT) composed of a charge amplifier outputting said voltage (V_0) function of the capacitance of the selected capacitor (C_{PIX}), having an inverting input (-), a feedback capacitor and a reset switch (S1), configuration switches for coupling said auxiliary capacitor (C_R) and said selected capacitor (C_{PIX}) as feedback capacitor and to said input of the amplifier, respectively or viceversa;

an analog-to-digital converter (ADC) converting said output voltage (V_0) in a corresponding multibit datum;

a processing and controlling microprocessor unit (COMPUTING CORE) performing noise filtering and real-time correction of data;

a digital output interface circuit (DIGITAL I/O) controlled by said microprocessor unit for outputting the data of the read values of capacitance of the sensor.

5. The system according to claim 4, further comprising a timing signal generator (WAVEFORM GENERATOR), controlled by said microprocessor unit, generating timing signals for said row and column selectors, for the biasing and reading circuit (READOUT) and for the

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converter (ADC), for synchronizing the operation phases of the circuits.

6. The system of claim 5, wherein said waveform generator (WAVEFORM GENERATOR) is composed of a shift register cyclically producing said timing signals with a certain frequency;

5 a finite state machine, controlled by the microprocessor unit, for configuring said shift register.

7. The system according to any of claims from 4 to 6, wherein said input interface circuit (ANAIO) comprises

5 a plurality of identical connection modules (ANAIOCIRCUIT) for grounding the deselected row plates and the deselected column plates, and coupling to said biasing and reading circuit (READOUT) the selected capacitor (C_{PIX}), in function of selection signals (ISIN, SELTHIS);

10 a selection logic circuit (ANAIOCONTROL) controlled by said microprocessor unit (COMPUTING CORE) producing said selection signals (ISIN, SELTHIS).